

157nm Lithography Semiconductor Lithography Workshop November 16th, 1999

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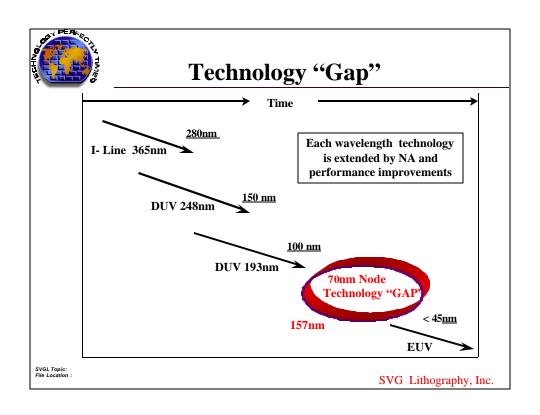
Why is 157nm Attractive Now?

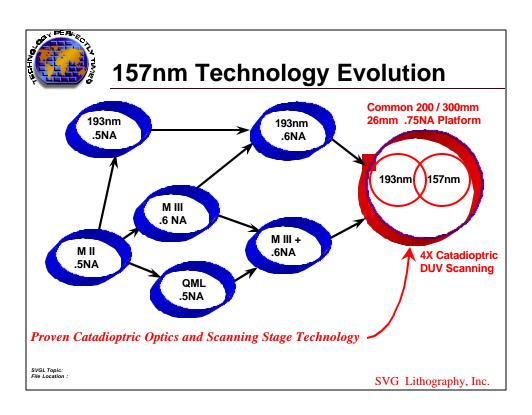
- A year and half ago it was not included in any discussions.
- Its attractive now because of advancements made in:
 - Light source, pulsed F2 Laser.
 - Optical material with transmission @ 157nm (CaF2)
- Laser development is moving rapidly.
- SVGL quietly worked the CaF2 material issue.
 - Demonstrated feasibility of the "cube"
- These are key enablers making an exposure tool possible.

Evolution not Revolution!

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SVGL 157nm Program Approach

- Identification of risk areas.
- Participation in Sematech CRADA.
- Collaboration with key partners:
 - CaF₂ Material
 - Laser Development
 - Modeling
 - Materials Testing
 - Purging & Contamination
 - Coating Development
- Proof of Concept Demonstration with Mini-Scanner.
- Full Field Demonstration.

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Risk Definition & Mitigation		
Key Risk Area	Issue	Mitigation Approach
1) Contamination	-Affects all aspects of the system, including build.	-Engagement of National Labs with investigations / studies.
2) Purging3) Resist / Processing	-Efficiency of system, purging of optical path incl reticle & wafer space. -Limited knowledge base.	-Combination of analysis and breadboard measurements. Evolution of X-ray. Engagement with Ultra High Vac -Extension of current resist chemistries
4) Reticle & Pellicle Mat'l and fabrication	-Reticle mat'l promising, pellicle is issue.	& develop via Sematech, MIT, othersMaterials testing via Sematech / MIT CRADA.
5) CaF2 Optical Mat'l	-B/S cube required for catadioptric design.	-3 suppliers, parallel effort, with key milestones at design reviews.
6) Optical Coatings	-Limited basic materials available.	-In-house and multi-subcontract effort. Phase approach with key milestones.
7) Opt Mat'l and Coating Laser Durability.	-Inconsistent mat'l quality and unknowns of coatings.	-Testing via Sematech / MIT CRADA. Also SVGL progams & CRADA's.
8) Advanced Metrology	-LWC req's improvement in all areas: Optics, align,	-All need to be addressed by industry in general. Extensive SVGL effort to
9) Laser Development	wafer, reticles, lithoImproved power and increased rep rate with decrease in consummables	develop novel litho testsLambda Physik is primary approach. Started 2 nd source with Cymer and engaged in discussions with Komatsu.
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157nm Mini-Scanner

Development of a 157nm Mini-Scanner

- Now under contract with Tropel for development of a small field 157nm optical train.
- Utilizes a modified Micrascan III+ as the body basis.
- Variable NA (.4 .75) and variable sigma (.3 .8)
- Provides SVGL a system for early demonstration of critical concepts (purging, contamination etc..)
- Provides customer base a system for early 157nm resist, reticle development.
- 4mm x 22mm scan field with overlay capability provides a vehicle for early process development.

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Full Field 157nm

Development of a Full Field 157nm Step & Scan

- 4X reduction, Variable NA (.4 to .75), 26mm x 34mm field continuos zoom illumination 26mm 11mm.
- Evolution of SVG catadioptric B/S cube design.
- Development of CaF₂ large size "cube" is key ingredient.
 - Engaged with multiple material partners
 - Results are encouraging.
- Still requires development of masks, pellicles and resists.
 - Collaborative interaction with Customers, Sematech and Labs.
- Utilizes the common VHNA 200mm/300mm platform.
 - Modified for the 157nm requirements
- Mini-scanner will be used to demonstrate key concepts.

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